

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. ASA-900-04	SERIAL NO. 10/757441
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT H. MIZUNO et al	
		FILING DATE 1/15/04	GROUP 2818

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
TL	AA	5,592,421	01/1997	Kaneko et al	—	—
TL	AB	6,107,836	08/2000	Kawahara et al	—	—
TL	AC	5,448,526	09/1995	Horiguchi et al	—	—
TL	AD	5,528,548	06/1996	Horiguchi et al	—	—
TL	AE	6,065,124	05/2000	Lee	—	—
TL	AF	6,222,355	04/2001	Ohshima et al	—	—
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TL	AL	8-234851	09/13/96	Japan	—	<input type="checkbox"/>	<input type="checkbox"/>
	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

TL	AR	IEEE ISSCC Digest of Technical Papers, Feb., 1997, pp. 66-67.
TL	AS	IEEE ISSCC Digest of Technical Papers, Feb., 1986, pp. 266-267.
TL	AT	IEICE Transaction on Electron, Vol. E75-C, No. 11, Nov. 1992, pp. 1333-1343.

EXAMINER Thoyke	DATE CONSIDERED 9/11/04
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.